

MOS FIELD EFFECT TRANSISTOR

2SK2341

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

The 2SK2341 is N-channel Power MOS Field Effect Transistor designed for high voltage switching applications.

FEATURES

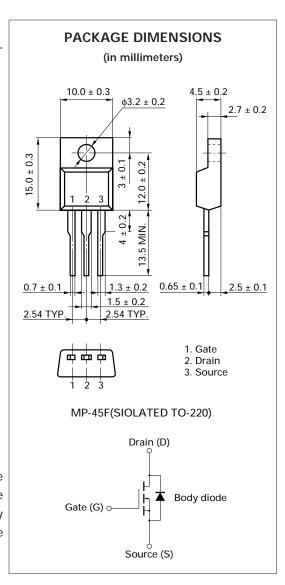
- Low On-state Resistance $R_{DS(on)} = 0.26 \ \Omega \ MAX. \ (V_{GS} = 10 \ V, I_{D} = 6.0 \ A)$
- Low Ciss Ciss = 1090 pF TYP.
- High Avalanche Capability Ratings

ABSOLUTE MAXIMUM RATINGS (TA = 25 °C)

Drain to Source Voltage	VDSS	250	V
Gate to Source Voltage	Vgss	±30	V
Drain Current (DC)	ID (DC)	±11	Α
Drain Current (pulse)	ID (pulse)*	± 44	Α
Total Power Dissipation (Tc = 25 °C)	P _{T1}	35	W
Total Power Dissipation (Ta = 25 °C)	P_{T2}	2.0	W
Storage Temperature	Tstg -55	to +150	°C
Channel Temperature	Tch	150	$^{\circ}\text{C}$
Single Avalanche Current	las**	11	Α
Single Avalanche Energy	Eas**	320	mJ

^{*}PW \leq 10 μ s, Duty Cycle \leq 1 %

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device is actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.



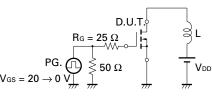
^{**}Starting Tch = 25 °C, RG = 25 Ω , VGS = 20 V ightarrow 0

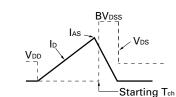


ELECTRICAL CHARACTERISTICS (TA = 25 °C)

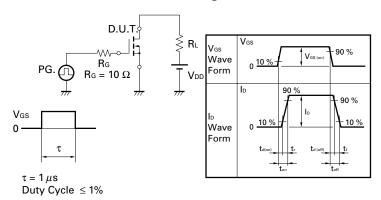
CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
Drain to Source On-state Resistance	RDS(on)		0.21	0.26	Ω	Vgs = 10 V, ID = 6 A
Gate to Source Cutoff Voltage	V _{GS(off)}	2.0		4.0	V	V _{DS} = 10 V, I _D = 1 mA
Forward Transfer Admittance	yfs	3.0			S	V _{DS} = 10 V, I _D = 6 A
Drain Leakage Current	IDSS			100	μΑ	V _{DS} = 250V, V _{GS} = 0
Gate to Source Leakage Current	Igss			±100	nA	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0$
Input Capacitance	Ciss		1090		pF	V _{DS} = 10 V
Output Capacitance	Coss		420		pF	Vgs = 0
Reverse Transfer Capacitance	Crss		80		pF	f = 1 MHz
Turn-On Delay Time	td(on)		20		ns	Vgs = 10 V
Rise Time	tr		20		ns	V _{DD} = 150 V
Turn-Off Delay Time	td(off)		50		ns	$I_D = 6 A$, $R_G = 10 \Omega$
Fall Time	t f		15		ns	R _L = 25 Ω
Total Gate Charge	Q _G		33		nC	Vgs = 10 V
Gate to Source Charge	Qgs		6.0		nC	ID = 11 A
Gate to Drain Charge	Q _{GD}		13		nC	V _{DD} = 200 V
Diode Forward Voltage	V _{F(S-D)}		1.0		V	IF = 11 A, VGS = 0
Reverse Recovery Time	trr		220		ns	1F = 11 A
Reverse Recovery Charge	Qrr		1.0		μC	di/dt = 50 A/μs

Test Circuit 1: Avalanche Capability

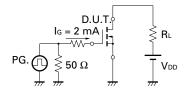




Test Circuit 2: Switching Time



Test Circuit 3: Gate Charge

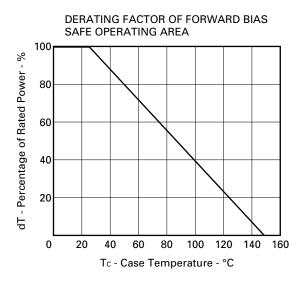


The application circuits and their parameters are for references only and are not intended for use in actual design-in's.

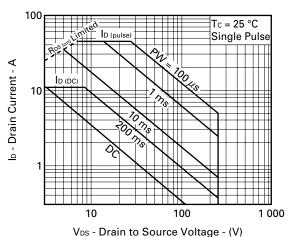
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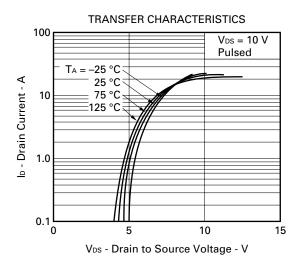
TYPICAL CHARACTERISTICS (TA = 25 °C)

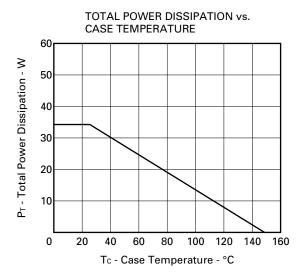


FORWARD BIAS SAFE OPRATING AREA

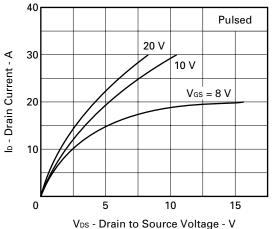


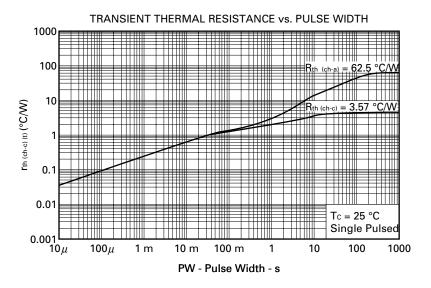
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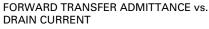


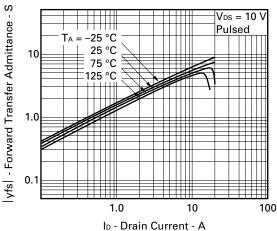


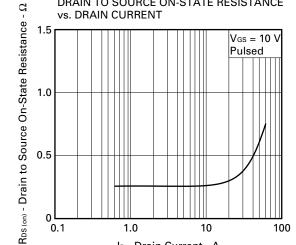












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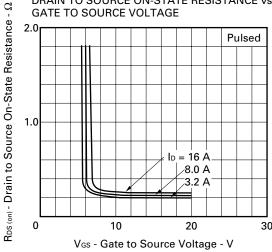
ID - Drain Current - A

10

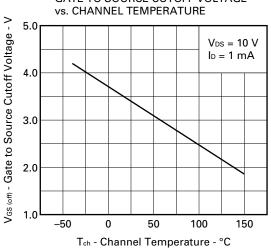
100

DRAIN TO SOURCE ON-STATE RESISTANCE

DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

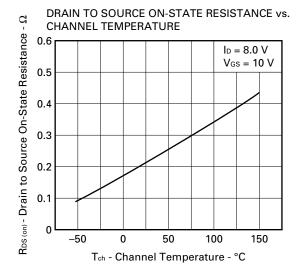


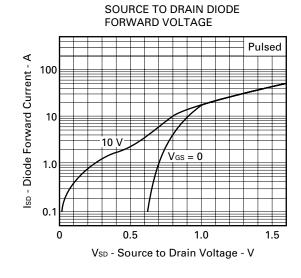
GATE TO SOURCE CUTOFF VOLTAGE

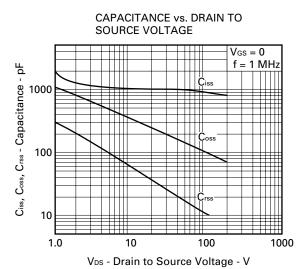


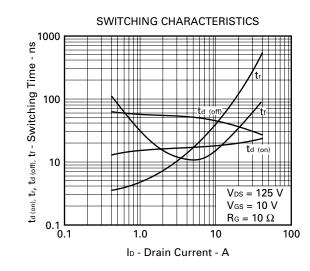
0.1

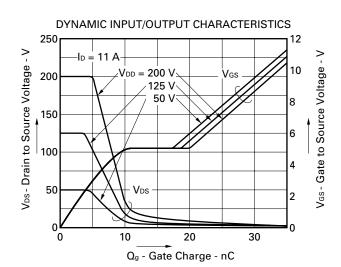


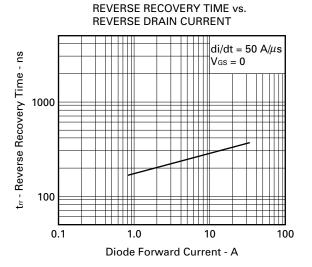














 10μ

INDUCTIVE LOAD A superscript of the property of the property

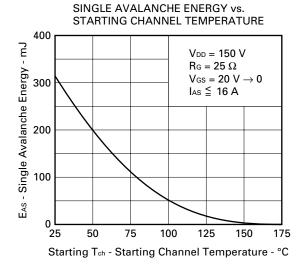
L - Inductive Load - H

1 m

10 m

 100μ

SINGLE AVALANCHE CURRENT vs.





REFERENCE

Document Name	Document No.
NEC semiconductor device reliability/quality control system.	TEI-1202
Quality grade on NEC semiconductor devices.	IEI-1209
Semiconductor device mounting technology manual.	IEI-1207
Semiconductor device package manual.	IEI-1213
Guide to quality assurance for semiconductor devices.	MEI-1202
Semiconductor selection guide.	MF-1134
Power MOS FET features and application switching power supply.	TEA-1034
Application circuits using Power MOS FET.	TEA-1035
Safe operating area of Power MOS FET.	TEA-1037

7

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Anti-radioactive design is not implemented in this product.

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